Search Notes



App	lica	tion/	Contr	ol No
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10577453

Applicant(s)/Patent Under Reexamination

VAINIO ET AL.

Examiner

Art Unit

MARCOS BATISTA

2617

SEARCHED

Class	Subclass	Date	Examiner
455	209	3/11/2008	mb
370	286	3/11/2008	mb

SEARCH NOTES

Search Notes	Date	Examiner
Consulted with Steve D'Aghosta	3/11/2008	mb
Consulted w/ lab TA Yogesh Aggarwal	3/11/2008	mb
Consulted with Lun-Yi Lao	3/11/2008	mb
Inventor's Name Search	10/22/2008	mb
East Search	10/22/2008	mb
Consulted with Rafael Perez Gutierrez	10/22/2008	mb

INTERFERENCE SEARCH		
INTEDEEDENCE SEADCH		

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